

<b>Notice of References Cited</b>	Application/Control No. 10/812,960	Applicant(s)/Patent Under Reexamination WU, CHIH-KANG	
	Examiner Jason M. Han	Art Unit 2875	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N	JP2001283624A	10-2001	Japan	Hirashiro et al.	F21V 008/00
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**NON-PATENT DOCUMENTS**

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	U	Kuodou:KK, English Translation of HIRASHIRO (JP 2001-283624), 10-2001, <a href="http://www19.ipdl.ncipi.go.jp/PA1/result/detail/main/wAAAPMa40IDA413283624P1.htm">http://www19.ipdl.ncipi.go.jp/PA1/result/detail/main/wAAAPMa40IDA413283624P1.htm</a> , Abstract pp. 1-2, Description pp. 1-7, Drawings pp.1-3
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